Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/699,933	SUZUKI, MASAYUKI	
Examiner	Art Unit	
D. Rutledge	2851	

	SEARCHED				
Class	Subclass	Date	Examiner		
355	53, 67-71	3/18/2005	DR		
359	364,365	3/18/2005	DR		
359	857-859	3/18/2005	DR		
250	492.2	3/18/2005	DR		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
355	53,67-71	3/18/2005	DR		
359	364,365	3/18/2005	DR		
359	857-859	3/18/2005	DR		
250	492.2	3/18/2005	DR		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
intermediate adj image same fourth same fifth; first near3 concave; second near3 concave; third near3 convex	3/18/2005	DR
fourth near3 concave; fifth near3 convex; six near3 concave; curvature near2 radius; lithograph\$3; (reticle or mask); (wafer	3/18/2005	DR
or substrate)	3/18/2005	DR